

Search Notes

Application/Control No.

10/700,632

Examiner

David J. Blanchard

Applicant(s)/Patent under
Reexamination

HOFFEE ET AL.

Art Unit

1643

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
SEQ ID Nos:1-10		4/2/2008	DB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
STIC search SEQ ID Nos:1-10 (results in SCORE)	4/2/2008	DB